



Topics

- In-house IP functions and IP metrics
- Key metrics of IP creation process
- IP portfolio management and its key metrics
- Key metrics in IP enforcement
- KPIs of IP exploitation
- IP risk management: key metrics
- Case studies

Learn how to
measure IP KPIs

Your Speaker



Donal O'Connell
Managing Director,
Chawton Innovation Services,
Chawton (UK)

Aims and objectives

In order to improve IP performance and to convince management of IP investments, understanding IP key metrics and measuring IP key performance indications (KPIs) is essential.

Attend this course and learn how to measure IP KPIs. Our experienced speaker will show you how to develop appropriate key metrics. Case studies will help you apply IP KPIs in practice.

Who should attend?

You work in an IP, patent or R&D department or as a patent attorney in private practice acting as external/outsourced IP managers and are asked to measure IP KPIs? Then this course is intended for you. Knowledge of IP is required.

Your benefits

After the course, you will

- know the essentials of IP metrics,
- know how to implement IP KPI measurement,
- be able to boost IP performance.

Your Speaker



Donal O'Connell
Managing Director,
Chawton Innovation
Services, Chawton (UK)

Donal is the Managing Director of Chawton Innovation Services which offers consultancy in the areas of innovation and IP management. He is formerly a VP of R&D and a Director of IP at Nokia where he worked for 21 years and gained wide and varied experience in the wireless telecoms industry.

Donal is also a Visiting Researcher at Imperial College Business School in London where he teaches about 'IP management'.

Donal's books include 'Inside the Patent Factory' and 'Harvesting External Innovation'. He is also written a large number of papers on various aspects of innovation and IP.

Since 2013, Donal has been included into the IAM 300. He is a graduate from NIHE Limerick (now The University of Limerick) in Ireland in '85, with a Degree in Electronic Engineering.

23 October 2019, 09:00-17:00

Overview of in-house IP functions

- Mission statement
- No one size fits all
- IP maturity & sophistication
- IP environment (value vs risk)

IP metrics in general

Key metrics of IP creation process

- Process description
- Comparing and contrasting different industry sectors
- Key metrics

IP portfolio management and its key metrics

- Process description
- The challenges
- Key metrics

Key metrics in IP enforcement

- Process description
- Some case studies
- Key metrics

KPIs of IP exploitation

- Process description
- Different ways of exploiting ip
- Key metrics

IP risk management: key metrics

- Process description
- Case studies
- Key metrics

Registration under
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Fax +49 6221 500-555

Registration Form

Yes, I will attend the practical course

IP Key Metrics

Yes, I agree that FORUM Institut may inform me about events and relevant expert content by:

email; and/or telephone.

I may withdraw my consent at any time.

Name

Position/Department

Company

Street

Postal Code/City/Country

Tel. No.

E-Mail

Contact person at office

Date, Signature

How to register

I Registration: +49 6221 500-500

I Conference-No. 19 10 182

I Internet:

www.forum-institut.com

I Date/Venue:

Wednesday, 23 October 2019 in Amsterdam
09.00-17:00

Amsterdam, NH Amsterdam Centre

Stadhouderskade 7 · NL 1054 ES Amsterdam

Tel. +31 20 685 1351

I Fee:

€ 1.120,00 (+ 21% VAT)

The fee includes course documentation (incl. free download) as well as midsession refreshments, lunch and certificate.

Invoice and confirmation will be forwarded to you.

Any Further Questions?



I am gladly at your disposal should you have any further questions about the practical course.

Jean-Claude Alexandre Ho

Lawyer, Conference Manager IP

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Cancellation Policy

Our general terms and conditions apply (as of 1. January 2016) and are available upon request.

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